

SMART: a SiPM Multichannel Asic for high Resolution Cherenkov Telescopes

F. Licciulli, G. De Robertis, F. Giordano, L. Di Venere

INFN – Section of Bari

- 1. ASIC & channel architectures
- 2. Channel simulations
- 3. SMART specifications
- 4. Measurements
- 5. Future perspectives

SMART Architecture



Analog Section:

- 16 Front-end channels:
 - Direct output: designed for photon-counting
 - Internal output: SiPM mean current measurement
- Global Bias: temperature and power supply independent
- 10 bit 1MHz SAR ADC for channel internal output conversion

Out_Ch15 **Digital Section:**

- Control Unit:
 - 1MHz SPI LVDS link
 - Channel & Global bias adj. bits
 - ADC control

Channel Architecture



Transient simulation: single pulse



Typical simulation for different gain settings: input signal 1ph (150fC), fast suppression For all the simulations an FBK 6x6mm2 SiPM has been used

INFN - Section Of Bari

Transient simulation: single pulse



Typical simulation for different gain settings: input signal 1ph (150fC), slow suppression

Noise Transient Simulation



Dark Rate 20MHz

SMART Specifications



- Dimensions: 2.1 x 3.9 mm²
- Technology node: 0.35um SiGe
- 16 analog channels
- Digital control and readout: LVDS SPI 1Mbps
- 6 global configuration bits + 8 local bits for each channel
- Chip power consumption: from 290mW to 420mW
- 64 pin CQFP package

SMART measurements: SiPM bias adjust



Analog channel input vs DAC control: LSB = 12.5mV, if DAC value = 0 the channel is off

SMART measurements: SiPM mean current



SMART slow monitoring output vs SiPM DC current for different CW laser light intensity, the measured sensitivity is $1.5ADC_ch/\mu A \Rightarrow LSB = 670 \text{ nA}$.

INFN - Section Of Bari

SMART measurements: output pulses



Single p.e for different gain adj.: Gain \approx 2-3 mV/p.e.

Setup:

- 4x4 NUV-HD3 matrix
- Vbias = 33V (Over Voltage = 6V)
- All channels active; light only on channel 7; channel 7 read.
- 50ps FWHM laser pulser



Single p.e for different shaping adj.: LSB \approx 0.8ns

SMART measurements: Charge Finger Plots

CHARGE DISTRIBUTION - tmax 10 CHARGE DISTRIBUTION - tmax 10 CHARGE DISTRIBUTION - tmax 10 240 -Entries 6999 CHARGE DISTRIBUTION - tmax 10 Mean 24.41 220 Entries 6999 220 F RMS 21.07 Mean 58.22 200 200 RMS 44.49 180 180 160 160 140 140 E Highest Input Z Lowest Input Z 120 120 Lowest gain Lowest gain 100 100 Fastest Shaping **Fastest Shaping** 80 80 60[60 40 40 F 20 0 0 50 100 150 200 250 60 0 20 40 80 100 120 0 **CHARGE DISTRIBUTION - tmax 10 CHARGE DISTRIBUTION - tmax 10** CHARGE DISTRIBUTION - tmax 10 CHARGE DISTRIBUTION - tmax 10 6999 Entries 220 Entries 6998 200 70.76 Mean Mean 104.1 RMS 50.04 200 RMS 84.31 180 180 160 160 140 Highest Input Z Lowest Input Z 140 120 Highest gain Highest gain 120 100 100 **Slowest Shaping** Slowest Shaping 80 80 60 40 60 40 20 20 12 مهماه 0 0 50 100 150 200 250 300 500 100 200 300 400 0

SMART measurements: dark pulses



Comparison between laser & dark pulses, a ripple is present:

- Laser trigger very noisy
- PCB parasitic feedback source of oscillations

SMART measurements



FBK HD3 single SiPM connected to one ASIC channel (no matrix), 50ps FWHM laser pulser Oscilloscope settings: horizontal axis 10ns/div, vertical axis 10mV/div

INFN - Section Of Bari

- Further characterization: xtalk, all SiPMs of the matrix lighted
- SMART & TARGET characterization
- New PCB design
- Second version of SMART?